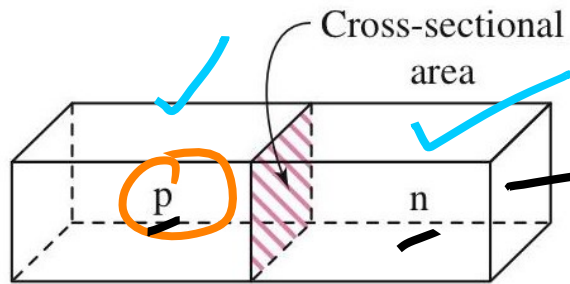
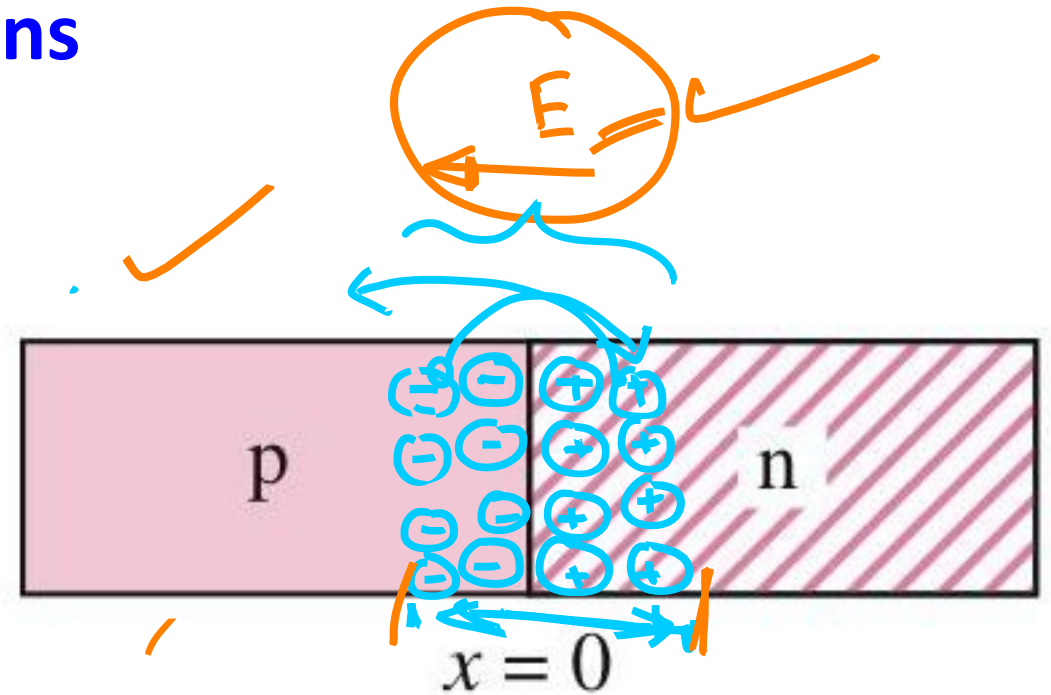
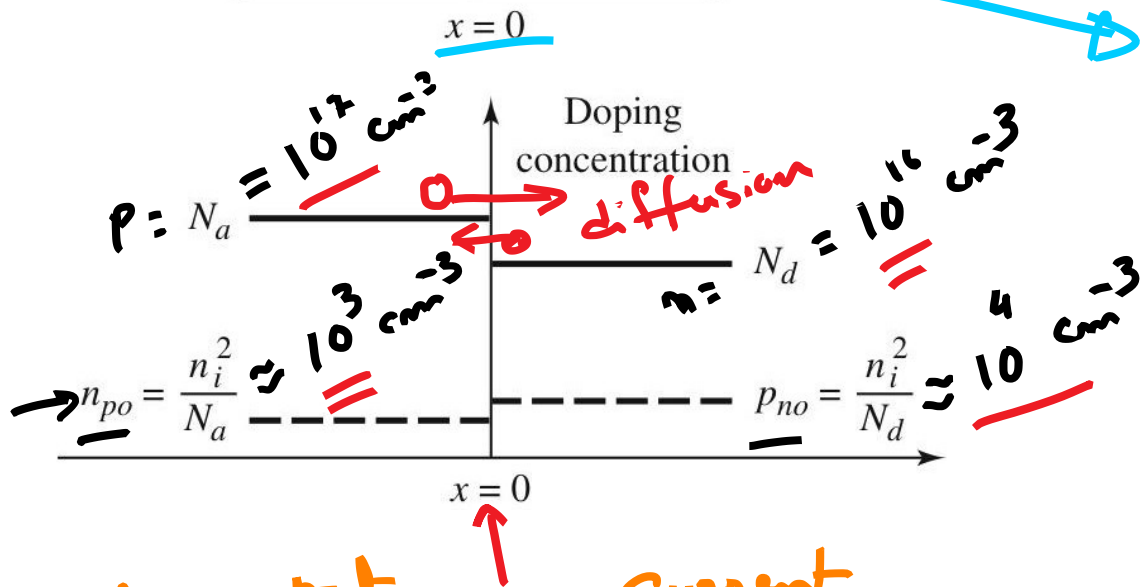


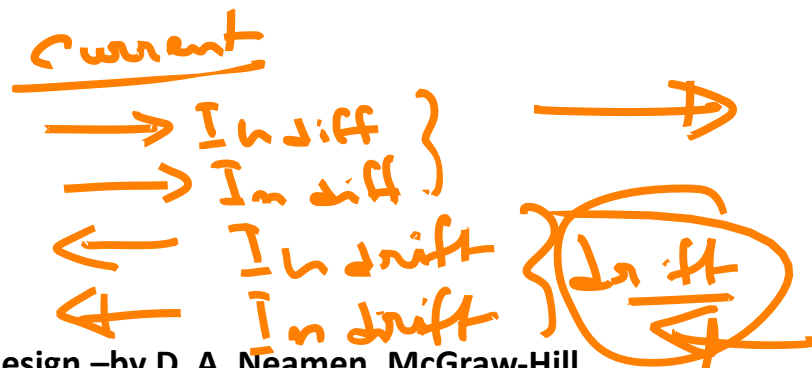
# ✓ p-n junctions



Si bar

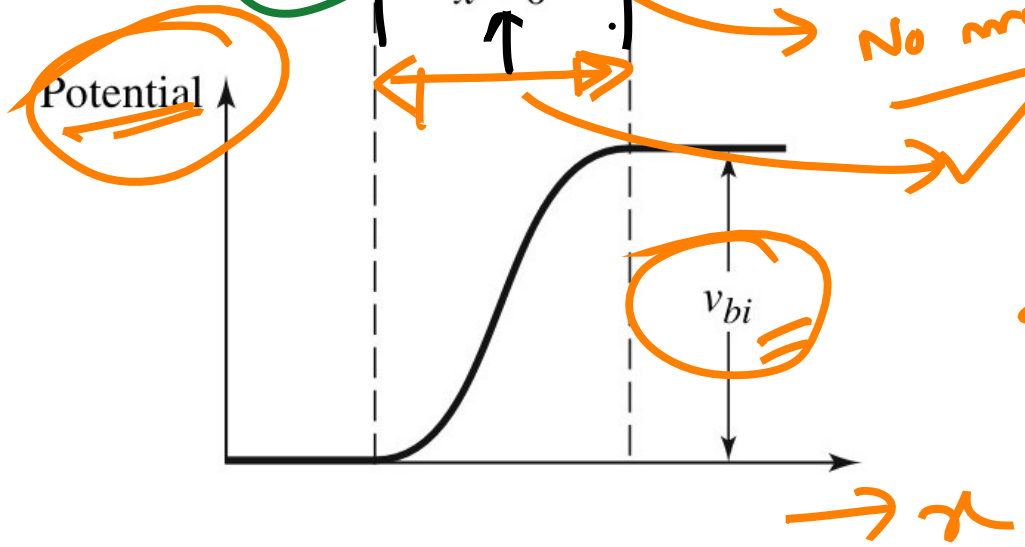
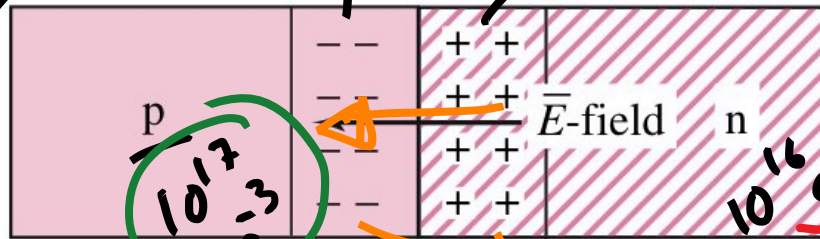


$I = 0$



# Built-in potential in p-n junction

Current-Voltage characteristics  
 $I \sim V$   
 Acceptance  
 1 cm



Depletion region

Si  
 GaAs  
 $10^{17} \text{ cm}^{-3}$   
 $10^{16} \text{ cm}^{-3}$

No mobile charge  
 Depletion region  
 Space-charge region

$$V_{bi} = \frac{KT}{q} \ln \left( \frac{N_A N_D}{n_i^2} \right)$$

$$= V_T \ln \left( \frac{N_A N_D}{n_i^2} \right)$$

→ 0.026 V at 300K

$E_g = 1.1 \text{ eV}$

$V_{bi} \approx 0.75 \text{ V}$

$V_{bi} \approx 0.81 \text{ V}$

for GaAs

$$V_{bi} = \frac{KT}{q} \ln \left( \frac{N_A N_D}{n_i^2} \right)$$

$\approx 1.28 \text{ V}$

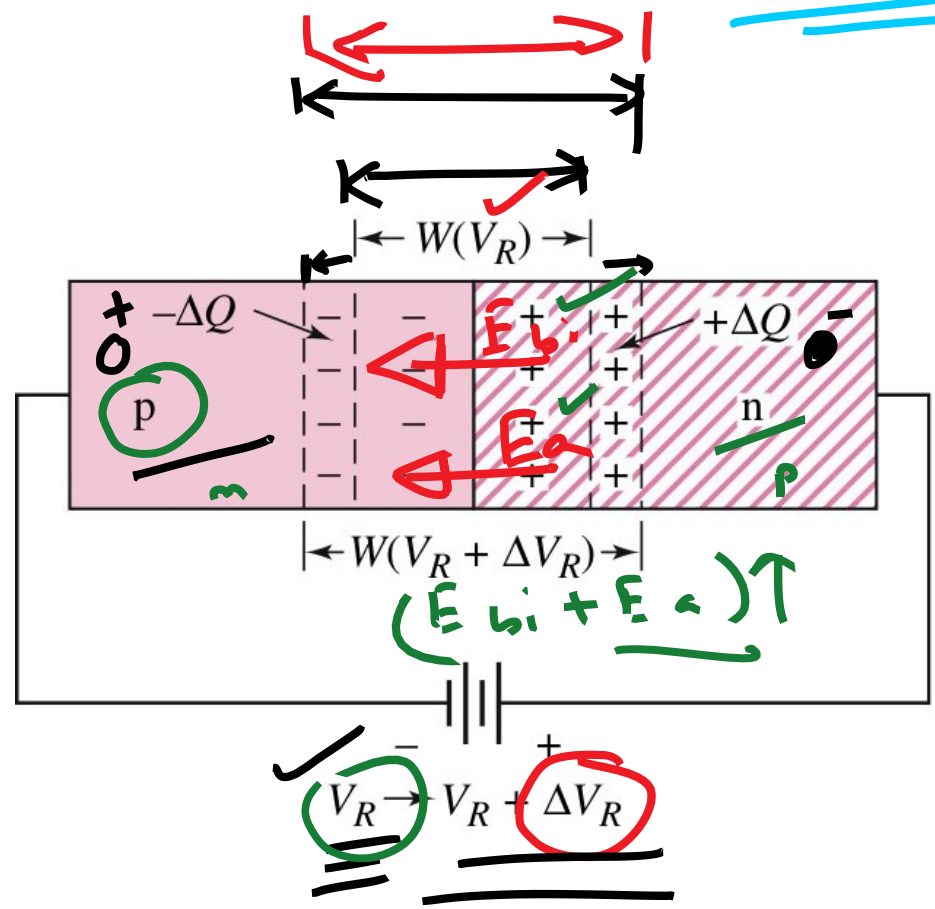
$1.8 \times 10^6 \text{ cm}^{-3}$

$E_g = 1.4 \text{ eV}$

\*

# Reverse biased p-n junction

$$W = \left[ \frac{2\epsilon(V_{bi} - V)}{q} \left( \frac{N_A + N_D}{N_A N_D} \right) \right]^{1/2}$$



Current

Diffusion component increase in E ↓

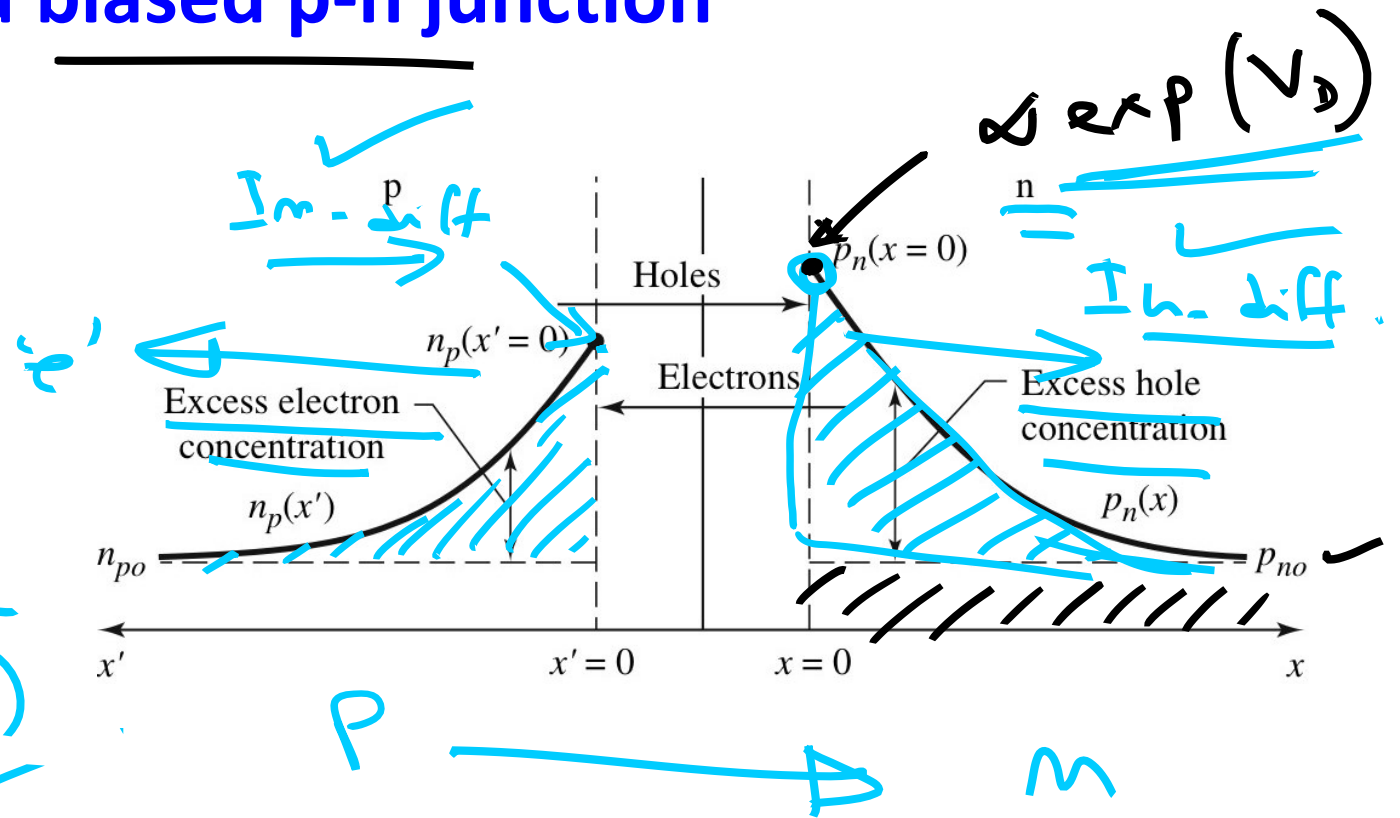
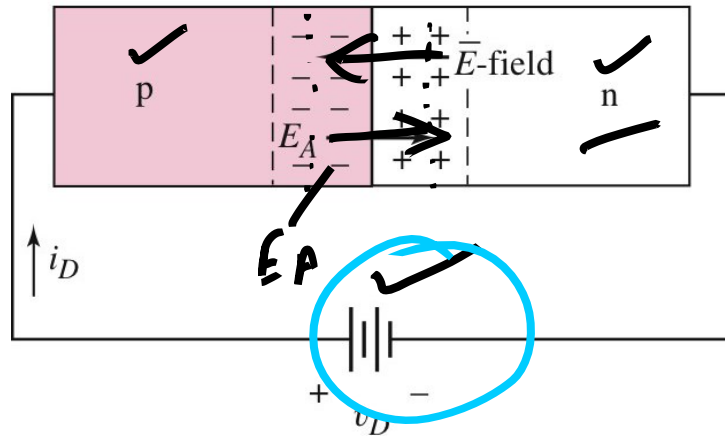
\* drift component??

remains same

In reverse bias the p-n junction current is low and almost constant.

$$\frac{E_{bi} - E_A}{E_{bi}}$$

# Forward biased p-n junction



diffusion  $I \propto \exp(\frac{V_D}{V_T})$

Reverse bias

$$I_0 \approx -I_s$$

$$I_0 = I_s \left[ \exp\left(\frac{V_D}{n V_T}\right) - 1 \right]$$

$\downarrow$  Reverse Saturation current  $I_s$   $\downarrow$  ideality factor  $n$   $\downarrow$   $1 \leq n \leq 2$   $\downarrow$   $< 10^{-10} \text{ A}$

# Current-voltage characteristics of p-n junction

$$I_D = I_S \left[ \exp\left(\frac{V_D}{nV_T}\right) - 1 \right]$$

$\uparrow 0.026 \text{ V}$

Reverse bias

$$I_D \approx -I_S$$

Forward bias  
 $V_D > 3V_T$

$$I_D = I_S \exp\left(\frac{V_D}{nV_T}\right) \quad [n=1]$$

Si-diode  
 $V_T \approx 0.6 \text{ V} - 0.7 \text{ V}$

